

INTERNATIONAL STANDARD

IEC
60384-22-1

First edition
2004-06

Fixed capacitors for use in electronic equipment –

Part 22-1:

Blank detail specification:

**Fixed surface mount multilayer capacitors
of ceramic dielectric, Class 2 –**

Assessment level EZ



Reference number
IEC 60384-22-1:2004(E)

Publication numbering

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CONTENTS

FOREWORD.....	3
INTRODUCTION.....	5
1 General data	7
1.1 Recommended method(s) of mounting (to be inserted).....	7
1.2 Dimensions	7
1.3 Ratings and characteristics	7
1.4 Normative references	8
1.5 Marking	8
1.6 Ordering information.....	8
1.7 Certified records of released lots.....	8
1.8 Additional information (not for inspection purposes)	8
1.9 Additional or increased severities or requirements to those specified in the generic and/or sectional specification	8
2 Inspection requirements	9
2.1 Procedures.....	9
Table 1 – Case size reference and dimensions	7
Table 2 – Values of capacitance and of voltage related to case sizes	7
Table 3 – Other characteristics	8
Table 4 – Test schedule for quality conformance inspection.....	9

INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –

**Part 22-1: Blank detail specification:
Fixed surface mount multilayer capacitors
of ceramic dielectric, Class 2 –
Assessment level EZ**

FOREWORD

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International Standard IEC 60384-22-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment

This standard and its related publications (CEI 60384-21, IEC 60384-21-1 and IEC 60384-22) cancel and replace IEC 60384-10 (1989) and its Amendments 1 (1993) and 2 (2000) as well as IEC 60384-10-1 (1989) and its Amendment 1 (1993).

The text of this standard is based on the following documents:

FDIS	Report on voting
40/1423/FDIS	40/1454/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.

The contents of the corrigendum of September 2004 have been included in this copy.

INTRODUCTION

Blank detail specification

A blank detail specification is a supplementary document to the sectional specification and contains requirements for style, layout and minimum content of detail specifications. Detail specifications not complying with these requirements may not be considered as being in accordance with IEC specifications nor shall they so be described.

In the preparation of detail specifications the content of 1.4 of the sectional specification shall be taken into account.

The numbers between square brackets on the first page of the detail specification correspond to the following information which shall be inserted in the position indicated.

Identification of the detail specification

- (1) The “International Electrotechnical Commission” or the National Standards Organization under whose authority the detail specification is drafted.
- (2) The IEC or National Standards number of the detail specification, date of issue and any further information required by the national system.
- (3) The number and issue number of the IEC or national generic specification.
- (4) The IEC number of the blank detail specification.

Identification of the capacitor

- (5) A short description of the type of capacitor.
- (6) Information on typical construction (when applicable).
- (7) Outline drawing with main dimensions which are of importance for interchangeability and/or reference to the national or international documents for outlines. Alternatively, this drawing may be given in an annex to the detail specification.
- (8) Application or group of applications covered and/or assessment level.
- (9) Reference data on the most important properties, to allow comparison between the various capacitor types.

	(1)	IEC 60384-22-1-ZZZ QC 30XXXX-ZZZ	(2)
ELECTRONIC COMPONENTS OF ASSESSED QUALITY IN ACCORDANCE WITH :	(3)	IEC 60384-22-1 QC 30 XXXX	(4)
Outline drawing : (see Table 1) (...angle projection) (Other shapes are permitted within the dimensions given)	(7)	FIXED SURFACE MOUNT MULTILAYER CAPACITORS OF CERAMIC DIELECTRIC, CLASS 2	(5)
			(6)
		Assessment level: EZ	(8)

Information on the availability of components qualified to this detail
specification is given in the IEC QC 001005.

(9)

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –

Part 22-1: Blank detail specification: Fixed surface mount multilayer capacitors of ceramic dielectric, Class 2 – Assessment level EZ

1 General data

1.1 Recommended method(s) of mounting (to be inserted)

(See 1.4.2 of IEC 60384-22).

1.2 Dimensions

Table 1 – Case size reference and dimensions

Case size reference	Dimension (mm)						
	L_1	W	H	L_2	L_3	L_4	---
When there is no case size reference, Table 1 may be omitted and the dimensions shall be given in Table 2, which then becomes Table 1.							
The dimensions shall be given as maximum dimensions or as nominal dimensions with a tolerance.							

1.3 Ratings and characteristics

Rated capacitance range (see Table 2)

Tolerance on rated capacitance

Rated voltage (see Table 2)

Category voltage (if applicable) (see Table 2)

Climatic category

Rated temperature

Category temperature (if applicable)

Tangent of loss angle

Insulation resistance

Temperature characteristics of capacitance ...%

Table 2 – Values of capacitance and of voltage related to case sizes

Rated voltage				
Category voltage ¹⁾				
Rated capacitance (in pF, nF and/ or µF)	Case size	Case size	Case size	Case size
¹⁾ If different from the rated voltage.				

1.4 Normative references

IEC 60384-1:1999, *Fixed capacitors for use in electronic equipment – Part 1: Generic specification*.

IEC 60384-22:2004, *Fixed capacitors for use in electronic equipment – Part 22: Sectional specification: Fixed surface mount multilayer capacitors of ceramic dielectric, Class 2*

IEC 60410:1973, *Sampling plans and procedures for inspection by attributes*

1.5 Marking

The marking of the capacitor, if applied, and the package shall be in accordance with the requirements of 1.6 of IEC 60384-22.

NOTE The details of the marking of the component and package shall be given in full in the detail specification.

1.6 Ordering information

Orders for capacitors covered by this specification shall contain, in clear or in coded form, the following minimum information:

- a) Rated capacitance.
- b) Tolerance on rated capacitance.
- c) Rated d.c. voltage.
- d) Temperature characteristics of capacitance.
- e) Number and issue reference of the detail specification and style reference.

1.7 Certified records of released lots

Required/not required.

1.8 Additional information (not for inspection purposes)

1.9 Additional or increased severities or requirements to those specified in the generic and/or sectional specification

NOTE Additions or increased requirements should be specified only when essential.

Table 3 – Other characteristics

<p>This table is to be used for defining characteristics which are additional to or more severe than those given in the sectional specification.</p>
--

2 Inspection requirements

2.1 Procedures

2.1.1

For qualification approval, the procedures shall be in accordance with 3.4 of IEC 60384-22.

2.1.2

For quality conformance inspection, the test schedule (Table 4) includes sampling, periodicity, severities and requirements. The formation of inspection lots is covered by 3.5.1 of IEC 60384-22.

Table 4 – Test schedule for quality conformance inspection

Subclause number and test ¹⁾	D or ND	Conditions of test ¹⁾	Number of specimens and number of non-conformances ²⁾			Performance requirements ¹⁾
			IL	<i>n</i>	<i>c</i>	
Group A inspection (lot-by-lot)						
Subgroup A0	ND			100 % ³⁾		
4.5.1 Capacitance		Frequency: ... Hz Measuring voltage: ... V r.m.s				Within specified tolerance
4.5.2 Tangent of loss angle (tan δ)		Frequency and measuring voltage same as in 4.5.1				As in 4.5.2
4.5.3 Insulation resistance		See detail specification for the method				As in 4.5.3.3
4.5.4 Voltage proof		See detail specification for the method				No breakdown or flashover

Table 4 – Test schedule for Quality Conformance Inspection (*continued*)

Subclause number and test ¹⁾	D or ND	Conditions of test ¹⁾	Number of specimens and number of non-conformances ²⁾			Performance requirements ¹⁾
			IL	<i>n</i>	<i>c</i>	
Subgroup A1 4.4 Visual inspection	ND		S-4	⁴⁾	0	As in 4.4.2 Legible marking and as specified in 1.5 of this specification
Subgroup A2 4.4 Dimension ⁵⁾	ND		S-3	⁴⁾	0	As specified in Table 1 of this specification
Group B inspection (lot-by-lot) Subgroup B1 4.5.5 Impedance (if required) 4.5.6 ESR (if required) 4.10 Solderability 4.10.3 Final measurements 4.17 Solvent resistance of the marking (if required) ⁶⁾	D	Frequency: 100 kHz Frequency: 100 kHz See detail specification for the method Visual examination Solvent: ... Solvent temperature: ... Method 1 Rubbing material: cotton wool Recovery: ...	S-3	⁴⁾	0	See detail specification See detail specification As in 4.10.3 Legible marking
Subgroup B2 4.6 Temperature characteristics of capacitance ⁷⁾	ND	Special preconditioning as in 4.1	S-2	⁴⁾	0	$\Delta C/C$: As in 4.6.3

Table 4 – Test schedule for Quality Conformance Inspection (*continued*)

Subclause number and test ¹⁾	D or ND	Conditions of test ¹⁾	Number of specimens and number of non-conformances ²⁾			Performance requirements ¹⁾
			<i>p</i>	<i>n</i>	<i>c</i>	
Group C inspection (periodic) Subgroup C1 4.15 Robstness of termination (if required) 4.9.2 Initial measurement 4.9 Resistance to soldering heat 4.9.5 Final measurements 4.16 Component solvent resistance (if required)	D	Test Ua1, Force: 2,5 N Test Ub, Method 1, Force: 2,5 N Number of bends: 1 Visual examination Special preconditioning as in 4.1 Capacitance See detail specification for the method Recovery: 24 h ± 2 h Visual examination Capacitance Solvent: ... Solvent temperature: ... Method 2 Recovery: ...	3	12	0 8)	No visible damage As in 4.9.5 As in 4.9.5 See detail specification
Subgroup C2 4.8 Substrate bending test 9) 4.8.1 Initial measurement 4.8.2 Final inspection	D	Deflection: ... Number of bends: ... Capacitance Capacitance (with printed board in bent position) Visual examination	3	12	0 8)	See detail specification ΔC/C ≤ 10 % No visible damage

Table 4 – Test schedule for Quality Conformance Inspection (*continued*)

Subclause number and test ¹⁾	D or ND	Conditions of test ¹⁾	Number of specimens and number of non- conformances ²⁾			Performance requirements ¹⁾
			<i>p</i>	<i>n</i>	<i>c</i>	
Subgroup C3 4.3 Mounting ¹⁰⁾	D	Substrate material: ... Visual examination Capacitance Tangent of loss angle Insulation resistance Voltage proof				As in 4.4.2 Within specified tolerance As in 4.5.2 As in 4.5.3.3 No breakdown or flashover

Table 4 – Test schedule for Quality Conformance Inspection (*continued*)

Subclause number and test ¹⁾	D or ND	Conditions of test ¹⁾	Number of specimens and number of non-conformances ²⁾			Performance requirements ¹⁾
			<i>p</i>	<i>n</i>	<i>c</i>	
Subgroup C3.1	D		6	27	0 8)	
4.7 Shear test ¹¹⁾		Visual inspection				No visible damage
		Special preconditioning as in 4.1				
4.11.2 Initial measurement		Capacitance				
4.11 Rapid change of temperature		T_A = Lower category temperature T_B = Upper category temperature Five cycles Duration t_1 = 30 min Recovery: (24 ± 2) h				
4.11.5 Final measurements		Visual examination Capacitance				No visible damage $\Delta C/C$: As in 4.11.5
4.12 Climatic sequence		Special preconditioning as in 4.1				
4.12.2 Initial measurement		Capacitance				
4.12.3 Dry heat		Temperature: upper category temperature Duration: 16 h				
4.12.4 Damp heat, cyclic, test Db, first cycle						
4.12.5 Cold		Temperature: lower category temperature Duration: 2 h Visual inspection				No visible damage
4.12.6 Damp heat, cyclic, test Db, remaining cycles		Recovery: $24 \text{ h} \pm 2 \text{ h}$				
4.12.7 Final measurements		Visual examination Capacitance Tangent of loss angle Insulation resistance				No visible damage, Legible marking $\Delta C/C$: As in 4.12.7 As in 4.12.7 As in 4.12.7

Table 4 – Test schedule for Quality Conformance Inspection (*continued*)

Subclause number and test ¹⁾	D or ND	Conditions of test ¹⁾	Number of specimens and number of non-conformances ²⁾			Performance requirements ¹⁾
			<i>p</i>	<i>n</i>	<i>c</i>	
Subgroup C3.2 4.13 Damp heat, steady state 4.13.2 Initial measurement 4.13.5 Final measurements	D	Special preconditioning as in 4.1 Capacitance Recovery: 24 h ± 2 h Visual examination Capacitance Tangent of loss angle Insulation resistance	6	15	0 8)	No visible damage, Legible marking $\Delta C/C$: As in 4.13.5 As in 4.13.5 As in 4.13.5
Subgroup C3.3 4.14 Endurance 4.14.2 Initial measurement 4.14.5 Final measurements	D	Special preconditioning as in 4.1 Duration: ...h Temperature: ...°C Voltage: ...V Capacitance Recovery: (24 ± 2) h Visual examination Capacitance Tangent of loss angle Insulation resistance	3	15	0 8)	No visible damage, Legible marking $\Delta C/C$: As in 4.14.5 As in 4.14.5 As in 4.14.5
Subgroup C3.4 4.18 Accelerated damp heat, steady state (if required) 4.18.1 Initial measurement 4.18.4 Final measurements	D	Duration: ... h Temperature: (85 ± 2) °C Humidity: (85 ± 3) % Insulation resistance Recovery: (24 ± 2) h Insulation resistance	6	15	0 8)	As in 4.18.1 As in 4.18.4
Subgroup C4 4.6 Temperature characteristic of capacitance	ND	Special preconditioning as in 4.1	6	9	0 8)	$\Delta C/C$: As in 4.6.3

- ¹⁾ Subclause numbers of tests and performance requirements refer to the sectional specification, IEC 60384-22 and Clause 1 of this specification.
- ²⁾ In this table : p = periodicity (in months), n = sample size, c = acceptance criterion (permitted number of non-conforming items), D = destructive, ND = non-destructive, IL = inspection level.
- ³⁾ 100 % testing shall be followed by re-inspection by sampling in order to monitor outgoing quality level by non-conforming items per million (ppm). The sampling level shall be established by the manufacturer. For the calculation of ppm values, any parametric failure shall be counted as a non-conforming item. In case one or more non-conforming items occur in a sample, this lot shall be rejected.
- ⁴⁾ Inspection Levels are selected from IEC 60410.
- ⁵⁾ This test may be replaced by in-production testing if the manufacturer installs Statistical Process Control (SPC) on dimensional measurements or other mechanisms to avoid parts exceeding the limits.
- ⁶⁾ This test may be carried out on capacitors mounted on a substrate.
- ⁷⁾ This subgroup may be omitted if a corresponding test is carried out on each manufacturing batch of dielectric material.
- ⁸⁾ If one non-conforming item is obtained, all the tests of the subgroup shall be repeated on a new sample and then no further non-conforming items are permitted. Release of product may continue during repeat testing.
- ⁹⁾ Not applicable to capacitors, which according to their detail specification shall only be mounted on alumina substrates.
- ¹⁰⁾ The capacitors found non-conformances after mounting shall not be taken into account when calculating the non-conformances for the following tests. They shall be replaced by spare capacitors.
- ¹¹⁾ Not applicable to capacitors with strip terminations.



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ISBN 2-8318-7550-1



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